

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MIYAKE ET AL.	
		Examiner Lana N. Le	Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0266378	12-2004	Fukamachi et al.	455/188.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11136151 A	05-1999	Japan	YOSHIKAWA et al.	H04B1/18
	O	JP 2003115778 A	04-2003	Japan	INOUE, KENICHI	H04B1/26
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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